Three-Dimensional Molecular Packing of Thin Organic Films of PTCDI-C_8 Determined by Surface X-ray Diffraction

Tobias N. Krauss[†], *Esther Barrena**[,†,‡], *Xue N. Zhang*[†], *Dimas G. de Oteyza*[†], *János Major*[†], *Volker Dehm*[§], *Frank Würthner*[§], *Leide P. Cavalcanti*[||], *and Helmut Dosch*[†,‡]

[†]Max-Planck-Institut für Metallforschung, Heisenbergstraße 3, 70569 Stuttgart, Germany

[‡]Institut für Theoretische und Angewandte Physik, Pfaffenwaldring 57, Universität Stuttgart, 70550 Stuttgart, Germany

[§]Institut für Organische Chemie, Am Hubland, Universität Würzburg, 97074 Würzburg, Germany

[||]European Synchrotron Radiation Facility (ESRF), 6 Rue Jules Horowitz, 38043 Grenoble, France

*E-mail: barrena@mf.mpg.de

Supporting Information

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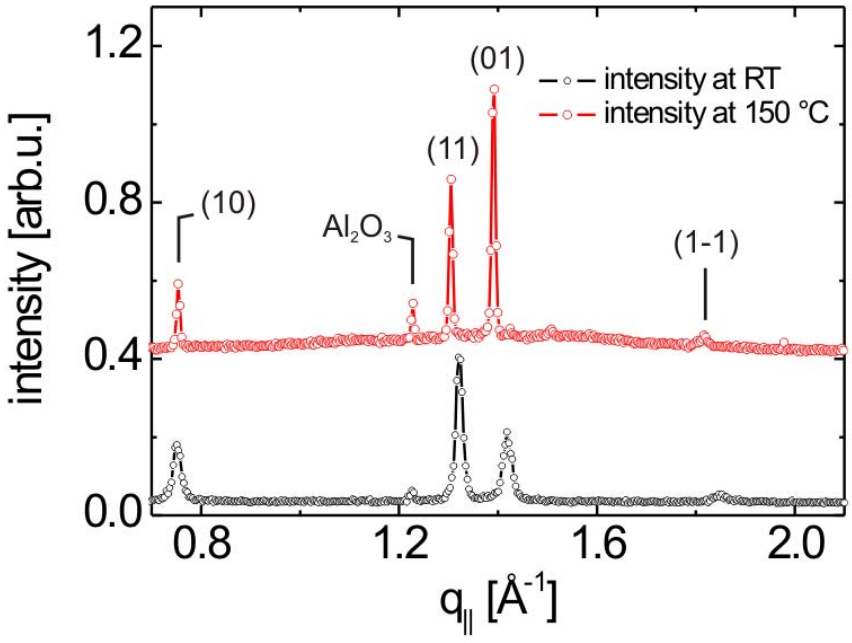

Figure S1. In-plane scans measured by grazing incidence X-ray diffraction from PTCDI-C_8 films grown on Al_2O_3 (11-20) at 150 °C and at room temperature. The X-ray measurements have been performed in-situ at these growth temperatures. Small variations of the in-plane unit cell are observed due to thermal expansion.